MAX1793EUE
Rev. A

RELIABILITY REPORT

FOR

MAX1793EUE

PLASTIC ENCAPSULATED DEVICES

August 29, 2002

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Written by

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Conclusion

The MAX1793 successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

Table of Contents

I. Device Description

A. General

The MAX1793 low-dropout linear regulator (LDO) operates from +2.5V to +5.5V and delivers a guaranteed 1A load current with a low 210mV dropout. The high-accuracy (±1%) output voltage is preset at an internally trimmed voltage (see *Ordering Information*) or can be adjusted from 1.25V to 5.0V with an external resistor-divider.

An internal PMOS pass transistor allows a low 125µA supply current, making the MAX1793 ideal for battery-operated portable equipment. Other features include a built-in reset output, low-power shutdown, and short-circuit and thermal overload protection. The MAX1793 is available in a 1.5W, 16-pin power TSSOP package, which is 30% smaller than a SOT223 package and only 1.1mm high.

B. Absolute Maximum Ratings

Item	Rating
IN, SHDN , RST to GND	-0.3V to +6V
OUT, SET to GND	-0.3V to (VIN + 0.3V)
Output Short-Circuit Duration	Infinite
Operating Temperature Range	-40°C to +85°C
Junction Temperature	+150°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (soldering, 10s)	+300°C
Power Dissipation	
16-Pin TSSOP-EP	1.5W
Derates above +70°C	
16-Pin TSSOP-EP	19mW/°C

II. Manufacturing Information

A. Description/Function:	Low-Dropout, Low IQ, 1A Linear Regulator
B. Process:	S8 - Standard 8 micron silicon gate CMOS
C. Number of Device Transistors:	845
D. Fabrication Location:	California, USA
E. Assembly Location:	Phillipines or Korea
F. Date of Initial Production:	April, 2000

III. Packaging Information

A. Package Type:	**16-Lead TSSOP**
B. Lead Frame:	Copper
C. Lead Finish:	Solder Plate
D. Die Attach:	Silver-filled Epoxy
E. Bondwire:	Gold (1.2 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	Buildsheet # 05-2301-0026
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard JESD22-A112:	Level 1

IV. Die Information

A. Dimensions:	60 X 72 mils
B. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide)
C. Interconnect:	TiW/ AlCu/ TiWN
D. Backside Metallization:	None
E. Minimum Metal Width:	.8 microns (as drawn)
F. Minimum Metal Spacing:	.8 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts: Jim Pedicord (Reliability Lab Manager)
Bryan Preeshl (Executive Director of QA)
Kenneth Huening (Vice President)

B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.

C. Observed Outgoing Defect Rate: < 50 ppm

D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in **Table 1**. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4389 \times 317 \times 2} \quad \text{(Chi square value for MTTF upper limit)}$$

Temperature Acceleration factor assuming an activation energy of 0.8eV

$\lambda = 3.43 \times 10^{-9}$ $\lambda = 3.43$ F.I.T. (60% confidence level @ 25°C)

This low failure rate represents data collected from Maxim's reliability qualification and monitor programs. Maxim also performs weekly Burn-In on samples from production to assure reliability of its processes. The reliability required for lots which receive a burn-in qualification is 59 F.I.T. at a 60% confidence level, which equates to 3 failures in an 80 piece sample. Maxim performs failure analysis on rejects from lots exceeding this level. The Burn-In Schematic (Spec.# 06-5538) shows the static circuit used for this test. Maxim also performs 1000 hour life test monitors quarterly for each process. This data is published in the Product Reliability Report (**RR-1M**) located on the Maxim website at http://www.maxim-ic.com .

B. Moisture Resistance Tests

Maxim evaluates pressure pot stress from every assembly process during qualification of each new design. Pressure Pot testing must pass a 20% LTPD for acceptance. Additionally, industry standard 85°C/85%RH or HAST tests are performed quarterly per device/package family.

C. E.S.D. and Latch-Up Testing

The PY28 die type has been found to have all pins able to withstand a transient pulse of ±2500V, per Mil-Std-883 Method 3015 (reference attached ESD Test Circuit). Latch-Up testing has shown that this device withstands a current of ±250mA.

Table 1

Reliability Evaluation Test Results

MAX1793UEU

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)				
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	317	0
Moisture Testing (Note 2)				
Pressure Pot	Ta = 121°C P = 15 psi. RH= 100% Time = 168hrs.	DC Parameters & functionality	135	0
85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality	77	0
Mechanical Stress (Note 2)				
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters	77	0

Note 1: Life Test Data may represent plastic D.I.P. qualification lots.
Note 2: Generic process/package data

Attachment #3

TABLE II. Pin combination to be tested. 1/ 2/

	Terminal A (Each pin individually connected to terminal A with the other floating)	Terminal B (The common combination of all like-named pins connected to terminal B)
1.	All pins except V_{PS1} 3/	All V_{PS1} pins
2.	All input and output pins	All other input-output pins

1/ Table II is restated in narrative form in 3.4 below.
2/ No connects are not to be tested.
3/ Repeat pin combination I for each named Power supply and for ground

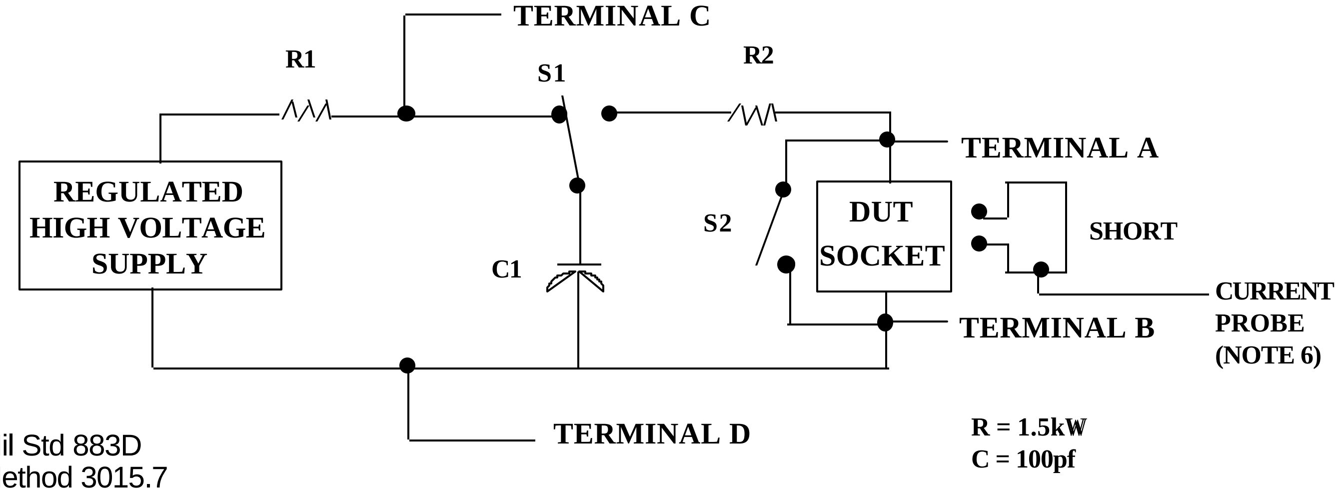
(e.g., where V_{PS1} is V_{DD}, V_{CC}, V_{SS}, V_{BB}, GND, $+V_{S,}$ $-V_{S}$, V_{REF}, etc).

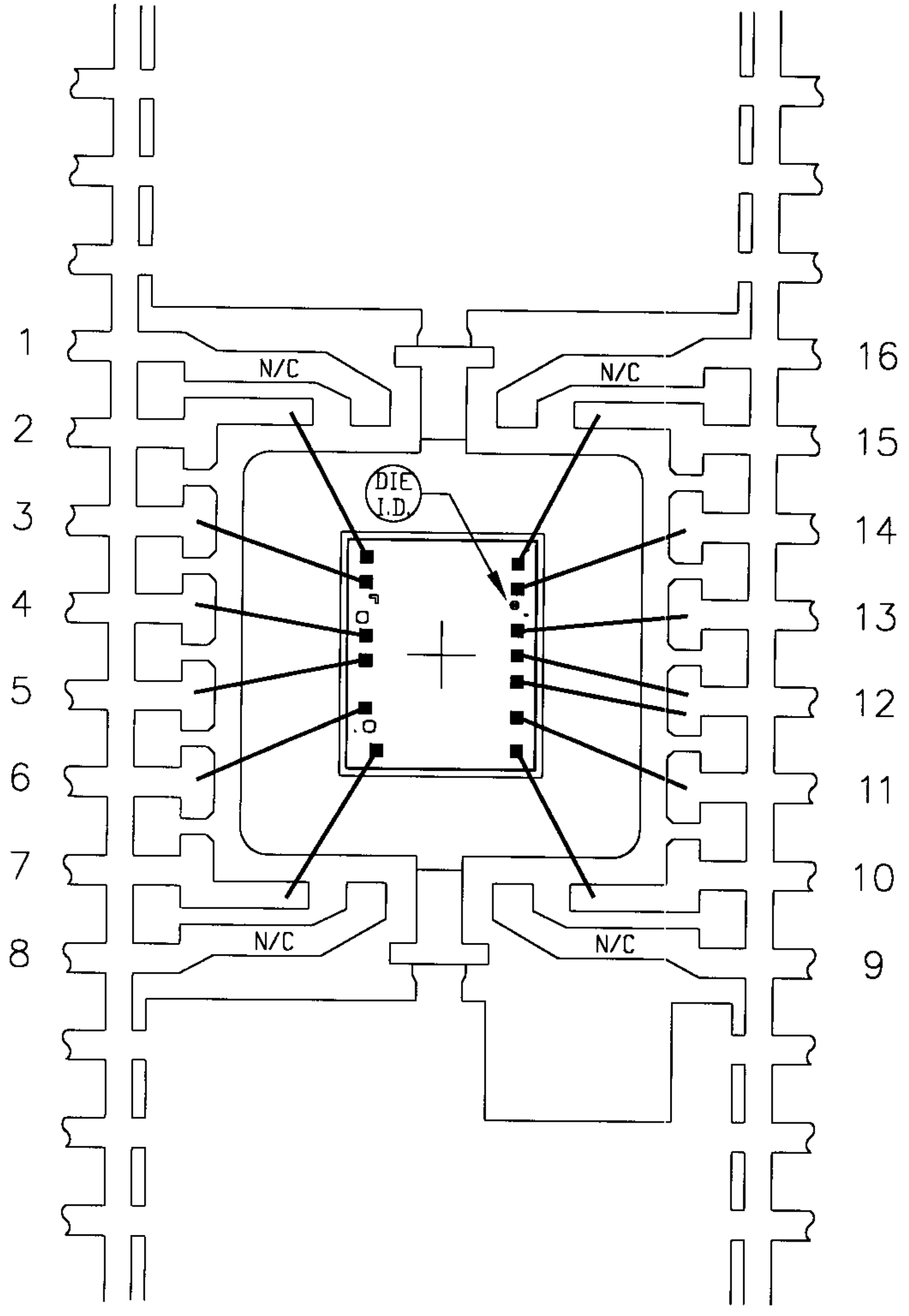
3.4 Pin combinations to be tested.

a. Each pin individually connected to terminal A with respect to the device ground pin(s) connected to terminal B. All pins except the one being tested and the ground pin(s) shall be open.

b. Each pin individually connected to terminal A with respect to each different set of a combination of all named power supply pins (e.g., V_{SS1}, or V_{SS2} or V_{SS3} or V_{CC1}, or V_{CC2}) connected to terminal B. All pins except the one being tested and the power supply pin or set of pins shall be open.

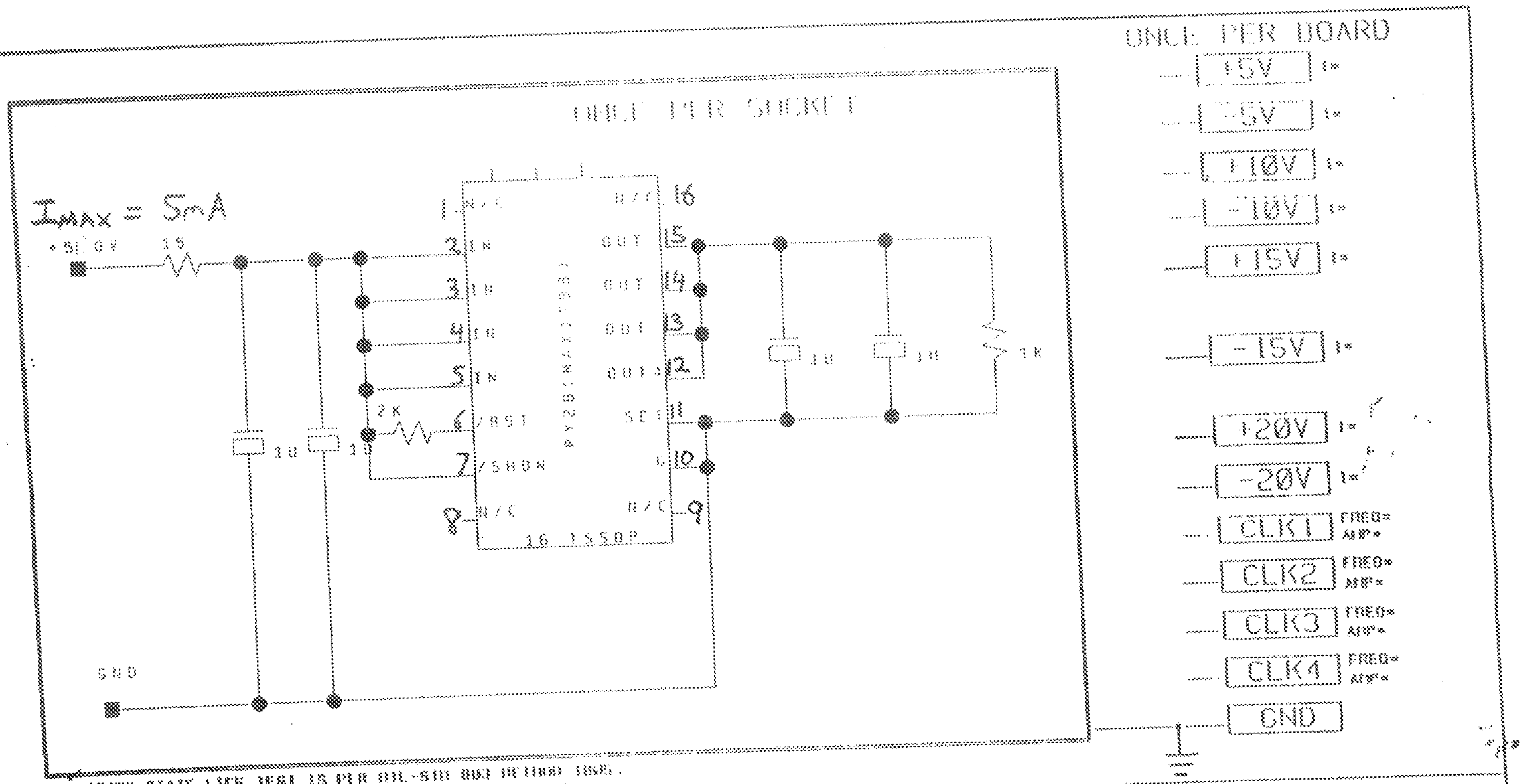
c. Each input and each output individually connected to terminal A with respect to a combination of all the other input and output pins connected to terminal B. All pins except the input or output pin being tested and the combination of all the other input and output pins shall be open.





PKG.CODE: U16E-3		APPROVALS	DATE
CAV./PAD SIZE: 118x118	PKG. DESIGN		

BUILDSHEET NUMBER:	REV.:
05-2301-0026	A



– STEADY STATE LIFE TEST IS PER MIL-STD 883 METHOD 1005.

– BURN-IN IS PER MIL-STD-883 METHOD 1015. COND. B

NOTES:

1. TEMPERATURE: 125C OR EQUIVALENT
2. TIME: 168 HOURS MIN, OR EQUIVALENT
3. ALL COMPONENTS AND MATERIAL MUST STAND 150C CONTINUOUS
4. APPROVED FOR (X) COMMERCIAL
   (A) MIL/883

SPEC. 06-5538 REV. B

DATE: 12/07/99

DRAWN BY: T. BEJSOVEC

MAXIM BURN-IN SCHEMATIC

DEVICE TYPE: MAX 1793
MAX 8869